with a uniform resistivity in space and with time.

The original impurity concentration in the substrate must be known; if two or more impurities are originally present they may be treated separately and the results superposed. The bulk resistivity of the deposited material near the final deposited surface must be known, either as inferred from knowledge of the behavior of the epitaxial deposition system or from direct measurement of the resistivity following deposition.³ Lastly, the solutions must be used with some discretion and ingenuity in superposing the effects of more than one deposition or **of** several species of impurities.

Obviously, the end result is not an exact description of the structure but rather an engineering approximation to the actual impurity distributions, since drastic

idealizations have been used in the analytical development. However, accounting for diffusion during epitaxy is informative as described here, and the accuracy of the accounting is consistent with the degree of control afforded by deposition systems and with available means of measurement of the properties of resulting devices.

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Correction

Casper W. Barnes, author of the paper "Conservative Coupling Between Modes of Propagation-a Tabular Summary," which appeared on pages **64-73,** of the January, **1964,** issue of PROCEEDINGS, has called the following to the attention of the Editor. Parts of the left-hand halves of Tables **111, IV, VII,** and **VIII,** were published incorrectly, and are reproduced on pages **296-299** as they should have appeared originally.

CONTRA-FLOW SKEW-HEWITIAN DIRECT COUPLING

297

Table IV CONTRA-FLOW HERMITIAN DIRECT COUPLING

298 *PROCEEDINGS OF THE IEEE March*

Table VI1 CONTRA-FLOW SKEW-HERMITIAN PARAMETRIC COUPLING

Conditions $v_{\text{gl}}v_{\text{g}2} \leq 0$ $p_1 p_2 \omega(\omega - \omega_p) > 0$ **I W** ω_{p} *w-w* **p** $\rightarrow \triangle$ β \leftarrow **2** $\boldsymbol{\beta}$ (w *w-4* **Diagram (uncoupled)** *w-9* **Diagram (coupled) Coup** *led Mode Equa* **t ton** $\frac{\partial}{\partial z}\begin{pmatrix} a_1(z,\omega) \\ a_2(z,\omega-\omega_p) \end{pmatrix} = -j\begin{pmatrix} \beta_1(\omega) & \kappa(\omega)e^{-j\beta}e^z \\ \kappa^*(\omega)e^{-j\beta}e^z & \beta_2(\omega-\omega_p) \end{pmatrix} \begin{pmatrix} a_1(z,\omega) \\ a_2(z,\omega-\omega_p) \end{pmatrix}$ *General Solution* (+ *z*-direction in direction of v_{g2}) $a_1(z,\omega) = \left\{ a_1(L,\omega) \begin{bmatrix} \cos \xi z - j(\Delta \beta/2 \xi) & \sin \xi z \\ \cos \xi L - j(\Delta \beta/2 \xi) & \sin \xi L \end{bmatrix} e^{j(\beta_1 - \Delta \beta/2)L} \right.$ + $a_2(0, \alpha - \alpha_p)$ $\left[\frac{j(\kappa/\xi) \sin \xi (L - z)}{\cos \xi L - j(\Delta \beta / 2\xi) \sin \xi L} \right]$ $e^{-j(\beta_1 - \Delta \beta / 2)^2}$ $a_2(z,\omega=\omega_p)=\left\{ \begin{array}{cc} -j\left(\kappa^*/\xi\right)\sin\xi\,z \\ a_1\left(L,\omega\right)\overline{\cos\xi L-j\left(\omega\beta/2\xi\right)}\,\sin\xi L}\end{array} \right\}e^{j\left(\beta_2+\Delta\beta/2\right)L}$ $+ a_2(0,\omega-\omega_p)\left[\frac{\cos \xi (L-z) - j\left(\Delta \beta /2\xi\right) \sin \xi (L-z)}{\cos \xi L - j\left(\Delta \beta /2\xi\right) \sin \xi L}\right] e^{-j\left(\beta_2 + \Delta \beta /2\right)z}$ $where$ $\xi = [\kappa \kappa^* + (\Delta \beta/2)^2]^{\frac{1}{2}}$ and $\Delta \beta = \beta_1(\omega) - \beta_2(\omega - \omega_p) - \beta_p$.

Table **VIII** CONTRA-FLOW **HEFhMITIAN PARAMETRIC COUFI1ING**